Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/010,212	LEE ET AL.	
Examiner	Art Unit	
Matthew F. DeSanto	3763	

	SEARCHED					
Class	Subclass	Date	Examiner			
609	9661,264 523-526, 103.04	2/5/06	Mrg			
664	103.07	\int				
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INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
	 					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
LAST uplskeljeurh + ihendr souh	2/5-106	lu p.1)		
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